

# LIST OF FIGURES

<b><u>FIG. No.</u></b>	<b><u>TITLE</u></b>	<b><u>PAGE No.</u></b>
<b>Fig. 1.1</b>	A cubic perovskite unit, cell $ABO_3$ , on the right, (b) corner-sharing of $BO_6$ octahedra in perovskite structure, $ABO_3$ and (c) oxygen vacancy migration path in perovskite structure, $ABO_3$ .	<b>2</b>
<b>Fig. 1.2</b>	Schematic representation of double perovskites $A_2BB'O_6$ unit cell and (b) single and double perovskite cubic structure, respectively.	<b>5</b>
<b>Fig. 1.3</b>	A schematic representation of the conductivity behaviour of an oxide ion conductor.	<b>21</b>
<b>Fig. 2.1</b>	Block diagram of various synthesis techniques.	<b>29</b>
<b>Fig. 2.2</b>	The image diagram representing the steps of solid state reaction method.	<b>30</b>
<b>Fig. 2.3</b>	Diagram representation of chemical reaction route with the appropriate steps.	<b>31</b>
<b>Fig. 2.4</b>	Block diagram of various characterization and analyses techniques.	<b>33</b>
<b>Fig. 2.5</b>	Schematic diagram of Bragg's law occurring through a crystal lattice.	<b>34</b>
<b>Fig. 2.6</b>	X-ray diffractometer working representation with image of Rigaku (Miniflex II desktop).	<b>35</b>
<b>Fig. 2.7</b>	Photograph of density kit of Mettler-Toledo.	<b>36</b>
<b>Fig. 2.8</b>	Schematic diagram representation of SEM (scanning electron microscope) with image of ZEISS (EVO-18).	<b>37</b>
<b>Fig. 2.9</b>	Schematic diagram of FTIR spectrometer working with photograph of Shimadzu spectrometer (FTIR-8400S).	<b>38</b>
<b>Fig. 2.10</b>	Schematic diagram of XPS (X-ray photoelectron spectroscopy).	<b>39</b>
<b>Fig. 2.11</b>	A Schematic design of XPS (X-ray photoelectron spectroscopy) working with photograph of XPS setup (KRATOS Amicus model).	<b>40</b>

<b>Fig. 2.12</b>	Block diagram of DSC/TGA measurement along with setup image of Mettler Toledo (TGA/DSC1 STARe thermal analyzer).	<b>41</b>
<b>Fig. 2.13</b>	A design of working and its corresponding photograph of dilatometry setup for TEC measurement (DIL 402 PC, NETZSCH).	<b>42</b>
<b>Fig. 2.14</b>	Computer controlled automated impedance analyser setup along with sample holder and furnace (6500 P Wayne Kerr, UK).	<b>43</b>
<b>Fig. 2.15</b>	The Probostat (Norecs, Norway) system impedance Analyzer (FRA, mod. SOLARTRON 1250 - Schlumberger), in a range of frequency between $10^{-1}$ – $10^5$ Hz.	<b>44</b>
<b>Fig. 2.16</b>	Equivalent circuit for a polycrystalline ceramic sample and corresponding plots of frequency response in the complex plane [Ref: R. Gerhardt, 1994].	<b>50</b>
<b>Fig. 3.1</b>	The X-ray diffraction pattern of $\text{La}_{1-x}\text{Gd}_x\text{CrO}_3$ ( $0.00 \leq x \leq 0.20$ ) system.	<b>54</b>
<b>Fig. 3.2</b>	Reitveld refinement of X-Ray diffraction pattern of $\text{La}_{1-x}\text{Gd}_x\text{CrO}_3$ ( $0.00 \leq x \leq 0.20$ ) system. Here Yobs, Ycal, Yobs-Ycal and Bragg_Position represent the experimental data, calculated data, the difference of experimental and calculated data and Bragg's positions, respectively.	<b>55</b>
<b>Fig. 3.3</b>	FTIR spectrum of $\text{La}_{0.99}\text{Gd}_{0.01}\text{CrO}_3$ .	<b>56</b>
<b>Fig. 3.4</b>	SEM micrograph of $\text{La}_{1-x}\text{Gd}_x\text{CrO}_3$ [(a) $x= 0.00$ , (b) $x= 0.01$ , (c) $x= 0.05$ , (d) $x= 0.10$ , (e) $x= 0.15$ , and (f) $x= 0.20$ ] system.	<b>57</b>
<b>Fig. 3.5</b>	Representative conductivity spectra of $\text{La}_{1-x}\text{Gd}_x\text{CrO}_3$ for (a) $x = 0.01$ and (b) $x = 0.10$ , at a few temperatures.	<b>58</b>
<b>Fig. 3.6</b>	Arrhenius representation of DC conductivity of $\text{La}_{1-x}\text{Gd}_x\text{CrO}_3$ ( $0.00 \leq x \leq 0.20$ ). The symbols denote the experimental (calculated) data points and the solid lines represent the linear fit to the data points.	<b>59</b>
<b>Fig. 3.7</b>	Variation of DC conductivity with dopant concentration $x$ in the system $\text{La}_{1-x}\text{Gd}_x\text{CrO}_3$ ( $0.00 \leq x \leq 0.20$ ).	<b>62</b>
<b>Fig. 3.8</b>	XPS spectra of the Cr2p level in the system $\text{La}_{1-x}\text{Gd}_x\text{CrO}_3$ ( $x= 0.00$ , $0.01$ and $0.20$ ).	<b>63</b>

<b>Fig. 4.1</b>	Rietveld refinement of X-ray diffraction pattern of various compositions (a) SNM00 (b) SNM05, (c) SNM10 and (d) SNM15. Here Yobs, Ycal, and Yobs-Ycal represent the experimental data, calculated data, and the difference of experimental and calculated data, respectively.	<b>67</b>
<b>Fig. 4.2</b>	Variation in lattice parameters as a function of the dopant concentration for the system SNM-x ( $0.00 \leq x \leq 0.15$ ).	<b>69</b>
<b>Fig. 4.3</b>	Field emission scanning electron micrograph of chemically etched various compositions (a) SNM00, (b) SNM05, (c) SNM10 and (d) SNM15.	<b>70</b>
<b>Fig. 4.4</b>	The variation of average TEC value for compositions SNM00, SNM05, SNM10 and SNM15.	<b>71</b>
<b>Fig. 4.5</b>	XPS spectra for compositions SNM00, SNM05, SNM10 and SNM15: (a) Sr-3d, (b) Ni-2p, (c) Mo-3d and (d) O-1s.	<b>73</b>
<b>Fig. 4.6</b>	The complex plane Impedance plots for the composition SNM05 at (a) 200 °C, (b) 275 °C, (c) 350 °C, (d) 425 °C, (e) 500 °C and (f) 600 °C.	<b>75</b>
<b>Fig. 4.7</b>	The complex plane Impedance plots for compositions (a) SNM00 (b) SNM05, (c) SNM10 and (d) SNM15 at 250 °C.	<b>77</b>
<b>Fig. 4.8</b>	Arrhenius $\log\sigma T$ vs. $1000/T$ plots of various compositions of the system SNM-x ( $0.00 \leq x \leq 0.15$ ).	<b>78</b>
<b>Fig. 4.9</b>	The plots of Resistances (R) vs. Temperature for the $\text{Sr}_2\text{NiMoO}_{6-\delta}$ (SNM00) sample in $\text{H}_2$ atmosphere.	<b>79</b>
<b>Fig. 4.10</b>	Arrhenius plots of conductivity for the $\text{Sr}_2\text{NiMoO}_{6-\delta}$ (SNM00) sample in $\text{H}_2$ and air atmosphere.	<b>80</b>
<b>Fig. 5.1</b>	The X-ray diffraction pattern of different samples (a) SLNM02, (b) SLNM04, (c) SLNM06, (d) SLNM08 and (e) SLNM10. Asterisk (*) indicates the $\text{SrMoO}_4$ phase.	<b>84</b>
<b>Fig. 5.2</b>	Reitveld refinement of X-ray diffraction pattern of different samples (a) SLNM02, (b) SLNM04, (c) SLNM06, (d) SLNM08 and (e) SLNM10. In this refinement, Yobs, Ycal, and Yobs-Ycal represent	<b>85</b>

the experimental data, calculated data, and the difference of experimental and calculated data, in that order.

- Fig. 5.3** DSC/TG curve for sintered SLNM04 in N<sub>2</sub> atmosphere from RT to 1000 °C. **87**
- Fig. 5.4** Field emission scanning electron micrograph of chemically etched various compositions (a) SLNM02, (b) SLNM04, (c) SLNM06, (d) SLNM08 and (e) SLNM10. **88**
- Fig. 5.5** XPS spectra for compositions SLNM02, SLNM04, SLNM06, SLNM08 and SLNM10: (a) Mo-3d, and (b) O-1s. **89**
- Fig. 5.6** The complex plane Impedance plots for the composition SLNM04: (a) 200 °C, (b) 275 °C, (c) 350 °C, (d) 475 °C, (e) 525 °C and (f) 600 °C. **91**
- Fig. 5.7** The modulus spectra for the composition SLNM04 at: (a) 200 °C, (b) 250 °C, (c) 300 °C and (d) 350 °C. **92**
- Fig.5.8** The complex plane Impedance plots for compositions: (a) SLNM02 (b) SLNM04, (c) SLNM06, (d) SLNM08, (e) SLNM10 and (f) combined plot for SLNM-x (0.02 ≤ x ≤ 0.10): at 375 °C. **94**
- Fig.5.9** Arrhenius logσ<sub>i</sub>T vs. 1000/T plots of various samples of the system SLNM-x (0.02 ≤ x ≤ 0.10). The inset depicts the variation of logarithms of conductivity with composition at 300 °C. **95**
- Fig.5.10** Variation of pre-exponential factor σ<sub>0</sub> and activation energy with respect to doping concentration x of the system SLNM-x (0.02 ≤ x ≤ 0.10). **97**
- Fig.5.11** The plots of Resistances (R) vs. Temperature for the Sr<sub>1.96</sub>La<sub>0.04</sub>NiMoO<sub>6-δ</sub> (SLNM04) sample in H<sub>2</sub> atmosphere. **98**
- Fig.5.12** Arrhenius plots of conductivity for the Sr<sub>1.96</sub>La<sub>0.04</sub>NiMoO<sub>6-δ</sub> (SLNM04) sample in H<sub>2</sub> and air atmosphere. **99**
- Fig.5.13** Rietveld refinement of X-ray diffraction pattern of samples (a) SCNM01, (b) SCNM02, (c) SCNM03, (d) SCNM04 and (e) SCNM05. Here Yobs, Ycal, and Yobs-Ycal represent the experimental data, **102**

calculated data, and the difference of experimental and calculated data, respectively.

<b>Fig.5.1 4</b>	TGA/DSC curve for SCNM01 in N <sub>2</sub> atmosphere.	<b>104</b>
<b>Fig.5.15</b>	Field emission scanning electron micrograph of chemically etched samples (a) SCNM01, (b) SCNM02, (c) SCNM03, (d) SCNM04 and (e) SCNM05.	<b>105</b>
<b>Fig.5.16:</b>	XPS spectra for compositions SCNM01, SCNM02, SCNM03, SCNM04 and SCNM05: (a) Mo-3d, and (b) O-1s.	<b>106</b>
<b>Fig.5.17</b>	The complex plane Impedance plots for the sample SCNM01 at (a) 300 °C, (b) 400 °C, (c) 500 °C, and (d) 600 °C.	<b>108</b>
<b>Fig.5.18</b>	Complex-plane modulus plots for the sample SCNM01 at (a) 300 °C, (b) 400 °C, (c) 500 °C and (d) 600 °C.	<b>109</b>
<b>Fig.5.19</b>	The complex plane Impedance plots for samples compositions SCNM01, SCNM02, SCNM03, SCNM04 and SCNM05 at 500 °C.	<b>110</b>
<b>Fig.5.20</b>	log $\sigma_i T$ vs. 1000/T plots for the system SCNM-x ( $0.01 \leq x \leq 0.05$ ).	<b>111</b>
<b>Fig.5.21</b>	The plots of Resistances (R) vs. Temperature for the Sr <sub>1.99</sub> Ce <sub>0.01</sub> NiMoO <sub>6-<math>\delta</math></sub> (SCNM01) sample in H <sub>2</sub> atmosphere.	<b>113</b>
<b>Fig.5.22.</b>	Arrhenius plots of conductivity for the SCNM01 sample in H <sub>2</sub> and air atmosphere.	<b>113</b>
<b>Fig.5.23.</b>	Reitveld refinement of X-ray diffraction pattern of different samples (a) SSNM01 (b) SSNM02, (c) SSNM03 and (d) SSNM04 and (e) SSNM05. In this refinement, Yobs, Ycal, and Yobs-Ycal represent the experimental data, calculated data, and the difference of experimental and calculated data, in that order.	<b>116</b>
<b>Fig.5.24</b>	DSC/TG curve for sintered sample SSNM01 in N <sub>2</sub> atmosphere from RT to 1000 °C.	<b>117</b>
<b>Fig.5.25</b>	Field emission scanning electron micrograph of fractured compositions (a) SSNM01, (b) SSNM02, (c) SSNM03, (d) SSNM04 and (e) SSNM05.	<b>118</b>
<b>Fig.5.26.</b>	XPS spectra for compositions SSNM01, SSNM02, SSNM03, SSNM04	<b>119</b>

	and SSNM05: (a) Mo-3d and (b) O-1s.	
<b>Fig.5.27.</b>	The complex plane Impedance plots for the composition SSNM05: (a) 250 °C, (b) 300 °C, (c) 350 °C, (d) 400 °C, (e) 500 °C and (f) 600 °C.	<b>121</b>
<b>Fig.5.28.</b>	The complex plane Impedance plots for compositions: (a) SSNM01, (b) SSNM02, (c) SSNM03, (d) SSNM04, (e) SSNM05 and (f) combined plot for SSNM-x ( $0.01 \leq x \leq 0.05$ ): at 450 °C.	<b>122</b>
<b>Fig.5.29.</b>	Arrhenius $\log\sigma T$ vs. $1000/T$ plots of various samples of the system SSNM-x ( $0.01 \leq x \leq 0.05$ ).	<b>123</b>
<b>Fig.5.30.</b>	The plots of Resistances as a function of temperature for the sample SSNM05 in H <sub>2</sub> atmosphere.	<b>125</b>
<b>Fig.5.31.</b>	Arrhenius plots of conductivity for the SSNM05 sample in H <sub>2</sub> and air atmosphere.	<b>126</b>
<b>Fig.6.1.</b>	Arrhenius plots of conductivity for the SNM, SLNM04, SCNM01 and SSNM05 samples in H <sub>2</sub> atmosphere. The inset depicts the variation of conductivity with composition at 600 °C.	<b>129</b>

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